



## Software Analysis and Testing for Large-Scale Software Systems

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### Message from the Guest Editors

Dear Colleagues,

This Special Issue aims to present the latest research and practices related to improving the dependability and quality of software systems. We solicit high-quality work describing original and unpublished results of theoretical, empirical, conceptual, and experimental research at any point in software quality assurance approaches.

Topics of interest include, but are not limited to:

- Reliability, availability, and efficiency of software systems;
- Software testing, verification, and validation;
- Software configuration;
- Program analysis, debugging and comprehension;
- Information and software quality assurance;
- Fault tolerance for software reliability improvement;
- Software vulnerabilities;
- Mining software repositories and software analytics;
- Software maintenance and evolution;
- Benchmarking, tools, industrial applications, and empirical studies;
- AI for software quality assurance;
- Software quality assurance for AI.





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## Message from the Editor-in-Chief

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